

Materials Science and Engineering Department, NIT Calicut

AFM, Park XE100

Photo of Instrument:



Instrument Name	AFM
Instrument Model & Serial No.	PARK XE-100, H077600327
Instrument Make	PARK SYSTEMS
Category of Instrument	Characterization and Testing
Description of Instrument	Atomic Force Microscopy
Instrument Technical Description and Major Specifications (This Specifications Limited to Major 5)	<ol style="list-style-type: none"> 1. To identify Topography 2. To identify I/V Spectroscopy 3. To identify F-D Spectroscopy 4. To identify Nano Indentation
Application of Instrument (Limited to Major 4 or 5)	<ol style="list-style-type: none"> 1. Topography analysis in Electronic Industry 2. Polymers/Biological sample application 3. Piezo electric
Type of Sample Required for Analysis / Testing (Quantity, Pre-Preparation, State etc.) Guidelines for Sample Submission – User Instructions	<p>Maximum Size : 2cm×2cm</p> <p>Film/Coated samples</p> <p>No Liquid/Powder samples</p>

Materials Science and Engineering Department, NIT Calicut

Types of Analysis / Testing	Testing
Faculty In-Charge Name / Email / Contact	Dr Soney Varghese Soneyva@nitc.ac.in
Technical Staff Name / Email / Contact	Anurag C anuragc@nitc.ac.in
Location of Instrument	SEM/SPM Center
Other Details	

User Charges:

S.NO.	Type of Analysis/ Testing	Internal - within Department of NITC	Internal - Other Departments NITC	External Academic Educational Institutes	National Labs	Industry
1			200/ Sample	1000/Sample	1000/Sample	2000/Sample

Slot Booking and Payment Work Flow:

Contact the Faculty In-charge and Technical Staff through email